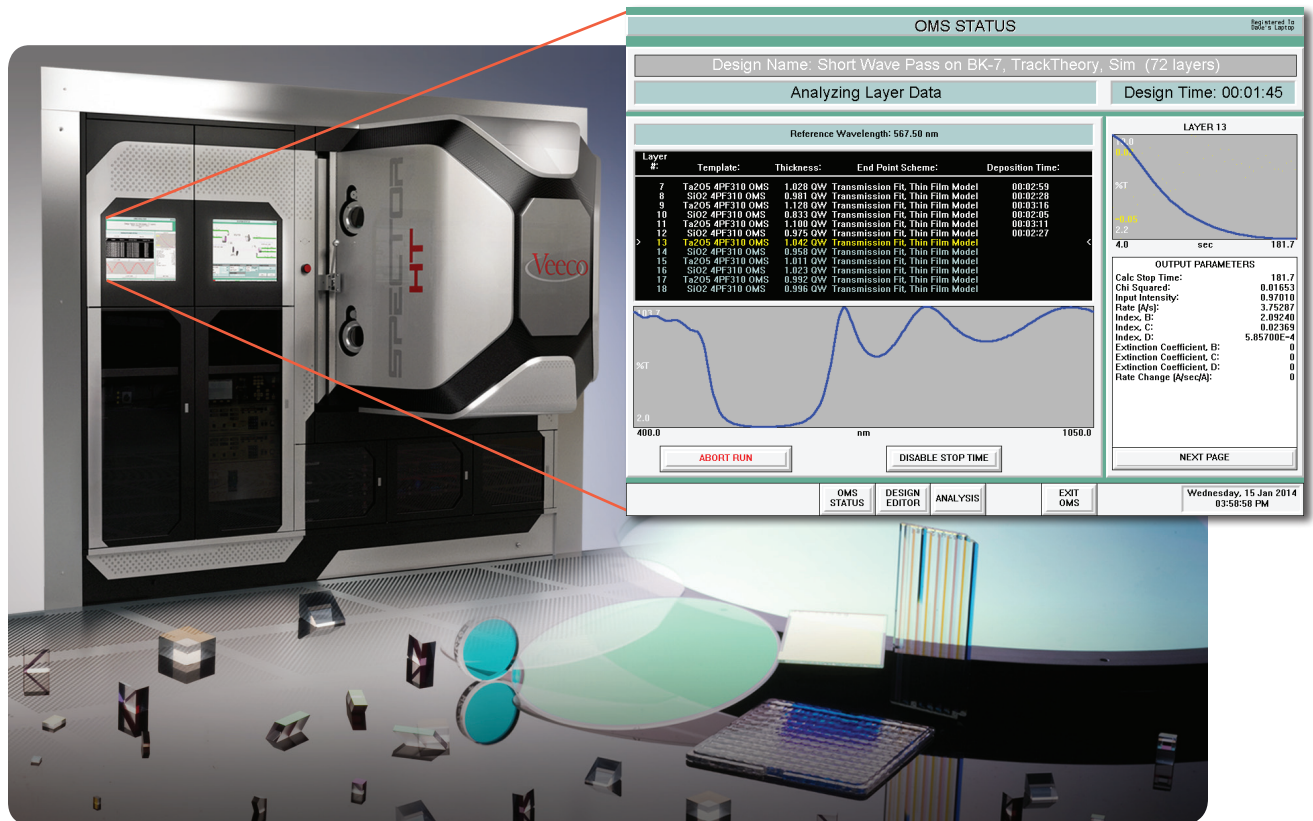


Quest Optical Monitor: The Evolution of Precision

Precision Control of Layer Endpoints Results in Improved Repeatability and Exceptional Process Control



- Up to a 10x improvement in layer thickness control compared to previous generations
- Increased production utilization through reduction in calibration runs
- Less than 0.1% repeatability even with non-consecutive runs
- Easy set-up with user-friendly interface
- Fully integrates into existing SPECTOR® and SPECTOR-HT™ IBD systems



Innovation. Performance. Brilliant.

Quest Optical Monitor

Veeco's Quest™ Optical Monitor provides non-quarterwave control directly on production substrates. Multiple algorithm choices and selectable wavelength ranges allow control of leading edge optical designs.

Hardware Specifications

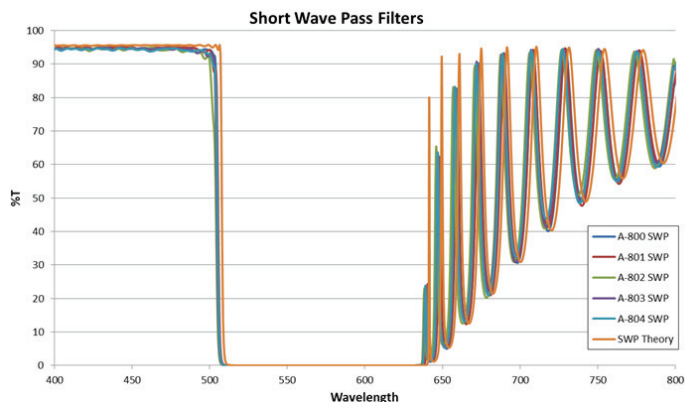
Measurement Type	Transmission
Control Range	400 – 1050nm
Control Resolution	Equivalent of 0.1 -0.3% random thickness error
Run to Run Centering	0.1 – 0.3%
Spectral Resolution	1.8nm FWHM avg
Monitoring Substrate	>25mm for Planetary >30mm for HSF
Monitoring Substrate	< 2 arc min
Operating Temp	10°C to 35°C
Relative Humidity	<80% from 10°C to 35°C (Non-condensing)

Design Set-Up

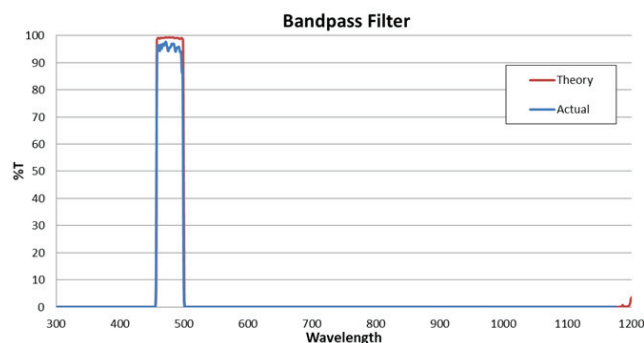
Designs can be manually set up or imported directly from

- OptiLayer
- Essential Macleod
- TFCalc

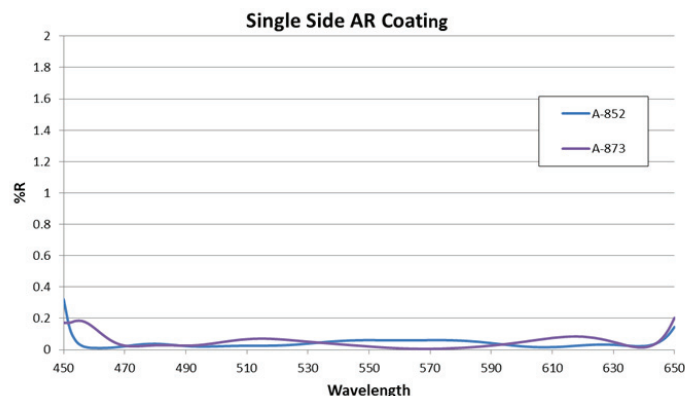
The OMS interface is flexible to achieve the best control scheme. Layer settings can be cascaded throughout the design, over select layer sets or established for each layer separately. Each layer can be controlled with a different control algorithm and different wavelength range. Test the design in the simulator to determine viability of the selected control scheme.



High Run to Run Reproducibility



Bandpass Filters With Wide OD6 Blocking



Broad Band AR Coatings Without Much Transmission Signal Change



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Veeco
1 Terminal Drive
Plainview, NY 11803
Tel: 516.349.8300 Fax: 516.349.8321

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